Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10526520	SCHULIST ET AL.
Examiner	Art Unit
Nguyen, Hai V	2618 ·

SEARCHED					
Class		Subclass	Date	Examiner	
370	335		12/22/2007	HN	

SEARCH NOTES				
Search Notes	Date	Examiner		
EAST search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM TDB) (see search history printout report)	12/21/2007; 01/03/2008	HN		

Subclass	Date	Examine
	Subclass	Subclass Date

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